

**Notice of References Cited**

Application/Control No.

10/501,928

Applicant(s)/Patent Under  
Reexamination  
HIRAI ET AL.

Examiner

EDMUND H. LEE

Art Unit

1791

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,866,316	02-1975	Takechi et al.	29/605
*	B	US-6,531,082	03-2003	Klee, Peter	264/257
*	C	US-6,069,430	05-2000	Tsunoda et al.	310/180
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 10058545	03-1998	JP	-----	-----
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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